

# Search Notes



Application/Control No.

10/699,157

Examiner

Kin-Chan Chen

Applicant(s)/Patent under Reexamination

TANAKA ET AL.

Art Unit

1765

## SEARCHED

Class	Subclass	Date	Examiner
438	706	10/28/2005	KCC
	710		
	714		
	712		
	723		
438	725		
438	637		
438	638	10/28/05	KCC

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
East Keywords search USPAT. USP4-pub. EPO, JPO, Derwent IBM-TDB, inventor search	10/28/2005	KCC